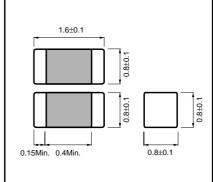
# Multi-layer ceramic chip capacitors

## MCH18 (1608 (0603) size, chip capacitor)

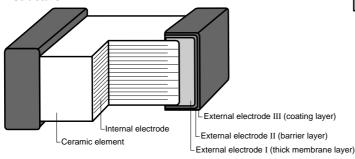
#### Features

- 1) Small size (1.6 x 0.8 x 0.8 mm) makes it perfect for lightweight portable devices.
- Comes packed either in tape to enable automatic mounting or in bulk cases.
- Precise uniformity of shape and dimentions highly efficient automatic mounting.
- 4) Barrier layer and end terminations to improve solderability.

#### ●External dimensions (Units : mm)



#### Structure

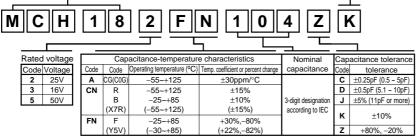


#### Product designation

Code	Product thickness	Packaging specifications	Reel	Basic ordering (pcs.)
K	0.8mm	Paper tape (width 8 mm, pitch 4 mm)	φ180mm (7in.)	4,000
L	0.8mm	Paper tape (width 8 mm, pitch 4 mm)	φ330mm (13in.)	16,000
С	0.8mm	Bulk case	_	15,000

Ree I(\phi180,\phi330mm): compatible with EIAJ ET-7200A Bulk case:compatible with EIAJ ET-7201A





<sup>\*</sup>The design and specifications are subject to change without prior notice. Before ordering or using, please check the latest technical specification.



## ●Capacitance range

For thermal compensation

For thermal compensation							
Part nur	MCH18						
Capacitance(pF)	Temperature characteristics	A (CG) (C0G)					
- Capaonanoc(pr)	Rated voltage Tolerance (V)	50					
0.5		<b>******</b>					
0.75							
1							
1.1							
1.2 1.3							
1.5							
1.6							
1.8							
2 2.2	C (+0.25pE)						
2.4	C ( ± 0.25pF)	<u> </u>					
2.7							
3							
3.3							
3.6							
3.9 4							
4.3							
4.7							
5		<u> </u>					
5.1 5.6							
6	D ( ± 0.5pF)						
6.2							
6.8							
7							
7.5 8							
8.2							
9		<b>****</b>					
9.1		×××××					
10 11							
12							
13							
15		<b>****</b>					
16 18							
20							
22							
24							
27 30							
33		<u>*******</u>					
36	J ( ± 5%)						
39							
43							
47 51							
56							
62		<b>******</b>					
68 75							
75							
82 91		<u>                                   </u>					
100							

Part nur	MCH18	
0	Temperature characteristics	A (CG) (C0G)
Capacitance (pF)	Rated voltage Tolerance (V)	50
110		<b>*****</b>
120		<b>******</b>
130		
150		<b>*****</b>
160		
180		<b>                                    </b>
200		
220		
240		<b>******</b>
270		
300	J ( ± 5%)	
330		
360		<b>*****</b>
390		
430		<b>******</b>
470		
510		<b>******</b>
560		
620		<b>*****</b>
680		
750		<b>******</b>
820		<b>******</b>
910		
1,000		

Product thickness (mm) 0.8 ± 0.1

<sup>\*</sup>The design and specifications are subject to change without prior notice. Before ordering or using, please check the latest technical specification.

High dielectric constant

Part number		MCH18				
Capacitance(pF)	Temperature characteristics	CN (R) (B) (X7R)		FN (F) (Y5V)		
Capacharios(p. )	Rated voltage (V)	50	25	50	25	16
	Tolerance	K (±	10%)	Z	(+80%, –20	%)
220		<b>*****</b>				
270 330		<b>*****</b>				
390						
470 560						
680						
820		XXXXXXX				
1,000						
1,200						
1,500						
1,800		- XXXXX		IXXXXXXI		
2,200 2,700						
3,300		<b>*****</b>				
3,900						
4,700						
5,600						
6,800						
8,200 10,000 (0.01μF)						
12,000						
15,000		××××				
18,000						
22,000		<b>******</b>		<b>******</b>		
27,000						
33,000			NOON			
39,000 47,000						
56,000						
68,000			<b>****</b>			
82,000			XXXXXX		XXXXXX	
100,000 (0.1μF)						
120,000 150,000						
180,000						
220,000						<b>******</b>
270,000						
330,000						
390,000						
470,000 560,000						
680,000						
1,000,000 (1μF) 1,200,000						
1,500,000						
1,800,000						
2,200,000						

Product thickness (mm) 0.8 ± 0.1

### Characteristics

Class 1 (For thermal compensation)

Temperature characteristics		A (CG) (C0G)	Test methods / conditions	
Item		(65)	(based on JIS C 5102)	
Operating temperature		−55°C ~ +125°C		
Nominal capacitance (C)		Must be within the specified tolerance range.	Based on paragraph 7.8 and paragraph 9 Measured at room temperature and standard humidity 1000pF or less Measurement frequency : 1± 0.1MHz	
Dissipation factor $(\tan \delta)$		100 / (400 + 20C)% or less (Less than 30 pF) 0.1% or less (30 pF or larger)	Measurement voltage : 1± 0.1\ Over 1000pF Measurement frequency : 1± 0.1\ Measurement voltage : 1± 0.1\	
Insulation resistance (IR)		10,000MΩ or 500MΩ·μF , whichever is smaller	Based on paragraph 7.6 Measurement is made after rated voltage is applied for $60 \pm 5s$ .	
Withstanding voltage		The insulation must not be damaged.	Based on paragraph 7.1 Apply 300% of the rated voltage for 1 to 5s then measure.	
Temperature cl	naracteristics	Within 0 $\pm$ 30ppm / $^{\circ}\text{C}$	The temperature coefficients in table 12, paragraph 7.12 are calculated at 20°C and high temperature.	
Terminal adherence		No detachment or signs of detachment.	Based on paragraph 8.11.2 Apply 5N for $10 \pm 1s$ in the direction indicated by the arrow. Pressure (5N) Capacitor	
	Appearance	There must be no mechanical damage.	Chip is mounted to a board in the	
Resistance to vibration	Rate of capacitance change	Must be within initial tolerance.	to vibration (type A in paragraph 8.2),	
	Dissipation factor (tanδ)	Must satisfy initial specified value.	and measured 24 ± 2 hrs. later. Board	
Solderability		At least 3 / 4 of the surface of the two terminals must be covered with new solder.	Based on paragraph 8.13 Soldering temperature : $235 \pm 5^{\circ}$ C Soldering time : $2 \pm 0.5$ s	
	Appearance	There must be no mechanical damage.		
	Rate of capacitance change	$\pm$ 2.5% or $\pm$ 0.25 pF , whichever is larger.	Based on paragraph 8.14	
Resistance to soldering	Dissipation factor (tanδ)	Must satisfy initial specified value.	Soldering temperature : $260 \pm 5$ °C Soldering time : $5 \pm 0.5$ s	
heat	Insulation resistance	10,000M $\Omega$ or 500M $\Omega$ ·μF , whichever is smaller	Preheating : 150 ± 10°C for 1 to 2 min.	
	Withstanding voltage	The insulation must not be damaged.	1 10 2 111111.	
	Appearance	There must be no mechanical damage.		
Temperature	Rate of capacitance change	$\pm~2.5\%\pm0.25~\text{pF}$ , whichever is larger.	Based on paragraph 9.3	
cycling	Dissipation factor (tanδ)	Must satisfy initial specified value.	Number of cycles : 5 Capacitance measured after 24 ± 2 hrs.	
	Insulation resistance	10,000M $\Omega$ or 500M $\Omega$ ·μF , whichever is smaller		
Humidity load - test	Appearance	There must be no mechanical damage.	Based on paragraph 9.9	
	Rate of capacitance change	$\pm$ 7.5% or $\pm$ 0.75 pF , whichever is larger.	Test temperature : 40 ± 2°C Relative humidity : 90% to 95%	
	Dissipation factor (tanδ)	0.5% or less	Applied voltage : rated voltage Test time : 500 to 524 hrs.	
	Insulation resistance	500M $\Omega$ or 25M $\Omega$ ·μF , whichever is smaller	Capacitance measured after 24 ± 2 hrs.	
High- temperature load test	Appearance	There must be no mechanical damage.	Based on paragraph 9.10	
	Rate of capacitance change	$\pm$ 3.0% or $\pm$ 0.3 pF , whichever is larger.	Test temperature : Max. operating temp.	
	Dissipation factor (tanδ)	0.3% or less	Applied voltage : rated voltage × 200% Test time : 1,000 to 1,048 hrs.	
	Insulation resistance	1,000M $\Omega$ or 50M $\Omega$ ·μF , whichever is smaller	Capacitance measured after 24 ± 2 hrs.	

<sup>\*</sup>The design and specifications are subject to change without prior notice. Before ordering or using, please check the latest technical specification.



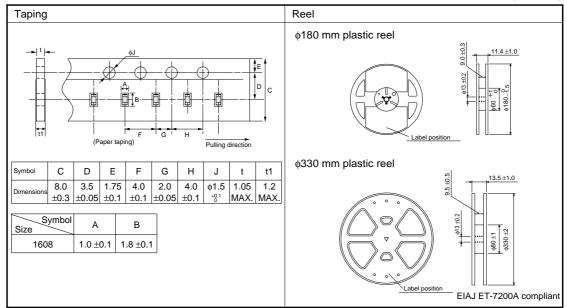
#### Class 2 (High dielectric constant)

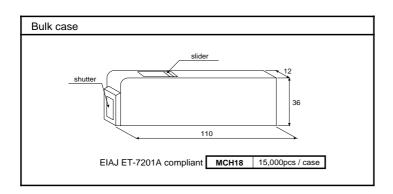
	lectric constant)				
Temperature characteristics		CN (R) (B) (X7R)	FN (F) (Y5V)	Test methods/conditions (based on JIS C 5102)	
Operating temperature		-55°C ~ +125°C	−30°C ~ +85°C		
Nominal capacitance (C)		Must be within the specified tolerance range.		Based on paragraph 7.8 Measured at room temperature and standard humidity	
Dissipation factor (tanδ)		2.5% or less (when rated voltage is 16V: 3.5% or less) (when rated voltage is 16V: 7.5% or less)		Measurement frequency: 1 ± 0.1 kHz	
Insulation resistance (IR)		10,000 MΩ or 500 MΩ · μF, whichever is smaller		Based on paragraph 7.6 Measurement is made after rated voltage is applied for $60 \pm 5s$ .	
Withstanding voltage		The insulation must not be damaged.		Based on paragraph 7.1 Apply 250% of the rated voltage for 1 to 5s then measur	
Temperature characteristics		Within ± 15%	+ 22, + 82%	The temperature coefficients in paragraph 7.12, table 8, condition B, are based on measurements carried out at 20°C, with no voltage applied.	
Terminal adherence		No detachment or signs of detachment		Based on paragraph 8. 11. 2.  Apply 5N for 10 ± 1s in the direction indicated by the arrow.	
	Appearance	There must be no mechanical damage.		Chip is mounted to a board in the manner shown on the right, subjected to vibration (type A in paragraph 8.2),	
Resistance to vibration	Rate of capacitance change	Must be within initial tolerance.			
	Dissipation factor (tanδ)	Must satisfy initial specified value.		and measured 48 ± 4 hrs. later.	
Solderability		At least 3/4 of the surface of the two terminals must be covered with new solder.		Based on paragraph 8. 13 Soldering temperature: $235 \pm 5^{\circ}$ C Soldering time : $2 \pm 0.5$ s	
	Appearance	There must be no mechanical damage.			
	Rate of capacitance change	Within ± 5.0%	Within ± 20.0%	Bd	
Resistance to soldering	Dissipation factor (tanδ)	Must satisfy initial specified value.		Based on paragraph 8. 14. Soldering temperature: 260 ± 5°C	
heat	Insulation resistance	10,000MΩ or 500MΩ $\cdot$ μF, whichever is smaller		Soldering time $: 5 \pm 0.5s$ Preheating $: 5 \pm 0.5s$ $: 150 \pm 10^{\circ}\text{C}$ for $1 \text{ to 2 min.}$	
	Withstanding voltage	The insulation must not be damaged.			
	Appearance	There must be no mechanical damage.			
Temperature	Rate of capacitance change	Within ± 7.5%	Within ± 20.0%	Based on paragraph 9.3 Number of cycles : 5	
cycling	Dissipation factor (tanδ)	Must satisfy initial specified value.		Capacitance measured after 48 ± 4 hrs	
	Insulation resistance	10,000M $\Omega$ or 500M $\Omega$ · μF, whichever is smaller		1	
Humidity load test	Appearance	There must be no mechanical damage.		Based on paragraph 9.9	
	Rate of capacitance change	± 12.5% or less	Within ± 30.0%	Test temperature: 40 ± 2°C	
	Dissipation factor (tanδ)	5.0% or less	7.5% or less (when rated voltage is 16V: 10.0%)	Relative humidity: 90% to 95% Applied voltage : rated voltage Test time : 500 to 524 hrs.	
	Insulation resistance	500MΩ or 25MΩ $\cdot$ μF, whichever is smaller		Capacitance measured after 48 ± 4	
High- temperature load test	Appearance	There must be no mechanical damage.			
	Rate of capacitance change	Within ± 10.0%	Within ± 30.0%	Based on paragraph 9.10	
	Dissipation factor ( $tan\delta$ )	5.0% or less	7.5% or less (when rated voltage is 16V: 10.0%)	Test temperature: Max. operating temp Applied voltage : rated voltage × 200% Test time : 1,000 to 1,048 hrs.	
	Insulation resistance	1,000MΩ or 50MΩ · μl	F, whichever is smaller	Capacitance measured after 48 ± 4	

<sup>\*</sup>The design and specifications are subject to change without prior notice. Before ordering or using, please check the latest technical specification.

## Packaging specifications

(Units : mm)





<sup>\*</sup>The design and specifications are subject to change without prior notice. Before ordering or using, please check the latest technical specification.

#### Electrical characteristics

## ■ A (C0G) Characteristics

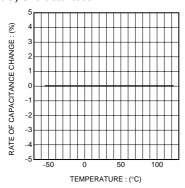


Fig.1 Capacitance - temperature characteristics

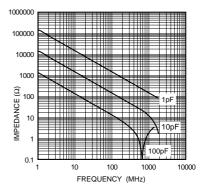


Fig.2 Impedance - frequency characteristics

## ■CN (X7R) Characteristics

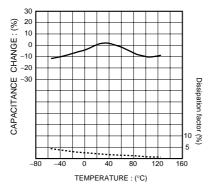


Fig.3 Capacitance - temperature characteristics

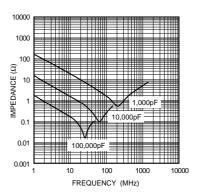


Fig.4 Impedance - frequency characteristics

## ■FN (Y5V) Characteristics

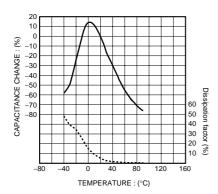


Fig.5 Capacitance - temperature characteristics

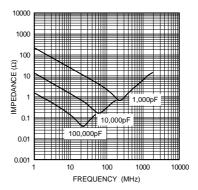
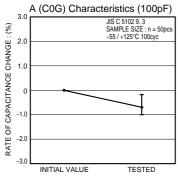


Fig.6 Impedance - frequency characteristics

<sup>\*</sup>The design and specifications are subject to change without prior notice. Before ordering or using, please check the latest technical specification.

## ■ Temperature cycling test





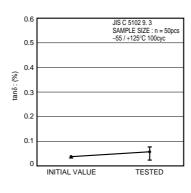


Fig.8 tanδ

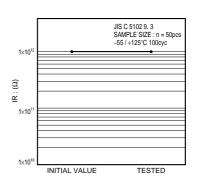


Fig.9 Insulation resistance

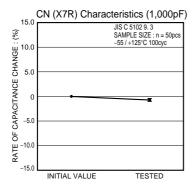


Fig.10 Rate of capacitance change

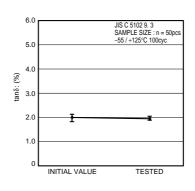


Fig.11 tanδ

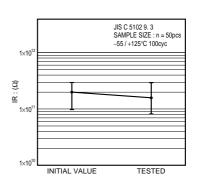


Fig.12 Insulation resistance

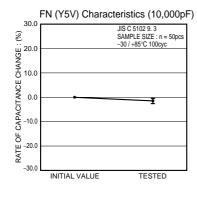
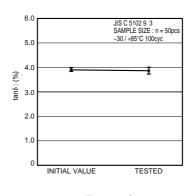


Fig.13 Rate of capacitance change





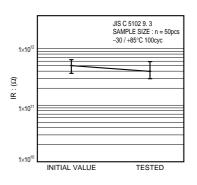
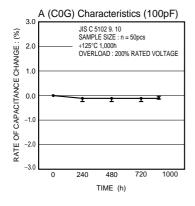


Fig.15 Insulation resistance

<sup>\*</sup>The design and specifications are subject to change without prior notice. Before ordering or using, please check the latest technical specification.

#### ■ High-temperature load test





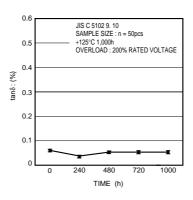


Fig.17 tanδ

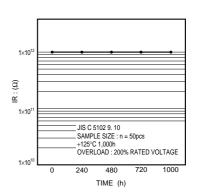


Fig.18 Insulation resistance

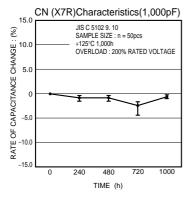


Fig.19 Rate of capacitance change

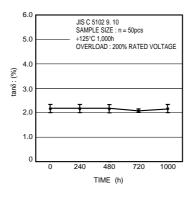


Fig.20  $\tan \delta$ 

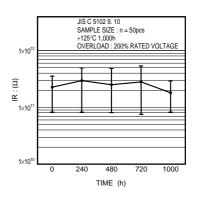


Fig.21 Insulation resistance

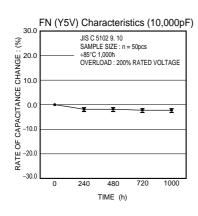


Fig.22 Rate of capacitance change

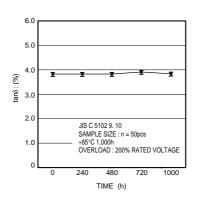


Fig.23  $tan\delta$ 

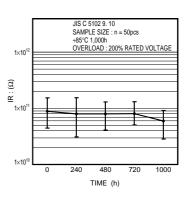
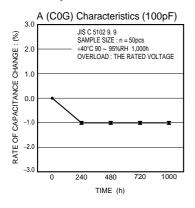
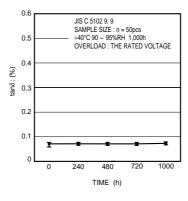


Fig.24 Insulation resistance

<sup>\*</sup>The design and specifications are subject to change without prior notice. Before ordering or using, please check the latest technical specification.

### ■ Humidity load test





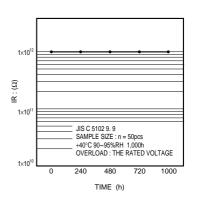
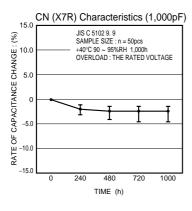
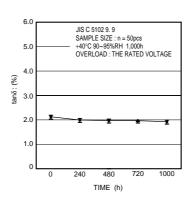


Fig.25 Rate of capacitance change

Fig.26  $\tan \delta$ 

Fig.27 Insulation resistance





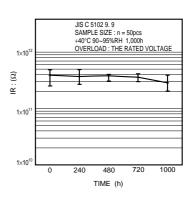
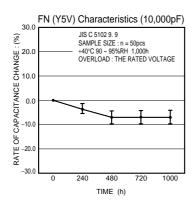
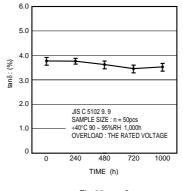


Fig.28 Rate of capacitance change

Fig.29  $tan\delta$ 

Fig.30 Insulation resistance





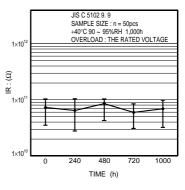


Fig.31 Rate of capacitance change

Fig.33 Insulation resistance

Fig.32 tanδ

<sup>\*</sup>The design and specifications are subject to change without prior notice. Before ordering or using, please check the latest technical specification.